Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/802,207	HAN ET AL.		
Examiner	Art Unit		
James A. Dudek	2871		

SEARCHED				
Class	Subclass	Date	Examiner	
349	153,155, 156,190	9/2/2005	JAD	
<u></u>				
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INTERFERENCE SEARCHED			
Subclass	Date	Examiner	
	9/2/2005	JAD	
		Subclass Date	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
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